Triple Line Receiver

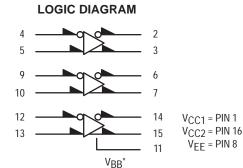
The MC10114 is a triple line receiver designed for use in sensing differential signals over long lines. An active current source and translated emitter follower inputs provide the line receiver with a common mode noise rejection limit of one volt in either the positive or the negative direction. This allows a large amount of common mode noise immunity for extra long lines.

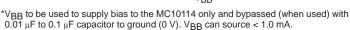
Another feature of the MC10114 is that the OR outputs go to a logic low level whenever the inputs are left floating. The outputs are each capable of driving 50 ohm transmission lines.

This device is useful in high speed central processors, minicomputers, peripheral controllers, digital communication systems, testing and instrumen– tation systems. The MC10114 can also be used for MOS to MECL interfacing and it is ideal as a sense amplifier for MOS RAM's.

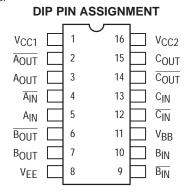
A V_{BB} reference is provided which is useful in making the MC10114 a Schmit trigger, allowing single–ended driving of the inputs, or other applications where a stable reference voltage is necessary. See MECL Design Handbook (HB205) pages 226 and 228.

- $P_D = 145 \text{ mW typ/pkg}$
- $t_{pd} = 2.4$ ns typ (Single Ended Input)
- t_{pd} = 2.0 ns typ (Differential Input)
- t_r , $t_f = 2.1$ ns typ (20%-80%)





When the input pin with the bubble goes positive, its respective output pin with bubble goes positive.

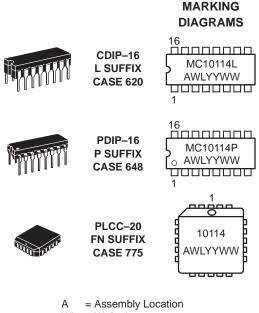


Pin assignment is for Dual–in–Line Package. For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).



ON Semiconductor

http://onsemi.com



WL = Wafer Lot YY = Year WW = Work Week

ORDERING INFORMATION

Device	Package	Shipping
MC10114L	CDIP-16	25 Units / Rail
MC10114P	PDIP-16	25 Units / Rail
MC10114FN	PLCC-20	46 Units / Rail

ELECTRICAL CHARACTERISTICS

				Test Limits							_
		Pin Under		-30°C +25°C			+85°C				
Characteristic		Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply Drain	Current	١E	8		39		28	35		39	mAdc
Input Current		l _{inH}	4		70			45		45	μAdc
		ICBO	4		1.5			1.0		1.0	μAdc
Output Voltage	Logic 1	VOH	2 3	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Output Voltage	Logic 0	VOL	2 3	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
Threshold Voltage	Logic 1	Vона	2 3	-1.080 -1.080		-0.980 -0.980			-0.910 -0.910		Vdc
Threshold Voltage	Logic 0	VOLA	2 3		-1.655 -1.655			-1.630 -1.630		-1.595 -1.595	Vdc
Reference Voltage		V _{BB}	11	-1.420	-1.280	-1.350		-1.230	-1.295	-1.150	Vdc
Common Mode Reje Test	ection	VOH	2 3	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
		VOL	2 3	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
Switching Times (50	DΩ Load)			Min	Max	Min	Тур	Max	Min	Max	ns
Propagation Delay		t4+2+ t4-2- t4+3- t4-3+	2 2 3 3	1.0 1.0 1.0 1.0	4.4 4.4 4.4 4.4	1.0 1.0 1.0 1.0	2.4 2.4 2.4 2.4	4.0 4.0 4.0 4.0	0.9 0.9 0.9 0.9	4.3 4.3 4.3 4.3	
Rise Time (20) to 80%)	t ₂₊ t ₃₊	2 3	1.5 1.5	3.8 3.8	1.5 1.5	2.1 2.1	3.5 3.5	1.5 1.5	3.7 3.7	
Fall Time (20) to 80%)	t ₂₋ t ₃₋	2 3	1.5 1.5	3.8 3.8	1.5 1.5	2.1 2.1	3.5 3.5	1.5 1.5	3.7 3.7	

ELECTRICAL CHARACTERISTICS (continued)

				TEST VOLTAGE VALUES (Volts)					
		@ Test Te	mperature	V _{IHmax}	VILmin	VIHAmin	VILAmax	V _{BB}	1
			–30°C	-0.890	-1.890	-1.205	-1.500	From	
			+25°C	-0.810	-1.850	-1.105	-1.475	Pin	
			+85°C	-0.700	-1.825	-1.035	-1.440	11	
			Pin	TEST V	OLTAGE AP	PLIED TO P	INS LISTED	BELOW	
Characteris	stic	Symbol	Under Test	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{BB}	Unit
Power Supply Drain Cur	rent	١E	8		4, 9, 12			5, 10, 13	mAdc
Input Current		linH	4	4	9, 12			5, 10, 13	μAdc
		l _{inL}	4		9, 12			5, 10, 13	μAdc
Output Voltage	Logic 1	Vон	2 3	4 9, 12	9, 12 4			5, 10, 13 5, 10, 13	Vdc
Output Voltage	Logic 0	V _{OL}	2 3	9, 12 4	4 9, 12			5, 10, 13 5, 10, 13	Vdc
Threshold Voltage	Logic 1	Vона	2 3	9, 12	9, 12	4	4	5, 10, 13 5, 10, 13	Vdc
Threshold Voltage	Logic 0	V _{OLA}	2 3	9, 12	9, 12	4	4	5, 10, 13 5, 10, 13	Vdc
Reference Voltage		V _{BB}	11					5, 10, 13	Vdc
Common Mode Rejectio	n Test	Vон	2 3						Vdc
		VOL	2 3						Vdc
Switching Times	(50 Ω Load)					Pulse In	Pulse Out		
Propagation Delay		^t 4+2+ ^t 4–2– ^t 4+3– ^t 4–3+	2 2 3 3			4 4 4 4	2 2 3 3	5, 10, 13 5, 10, 13 5, 10, 13 5, 10, 13 5, 10, 13	ns
Rise Time	(20 to 80%)	^t 2+ t3+	2 3			4 4	2 3	5, 10, 13 5, 10, 13	
Fall Time	(20 to 80%)	t ₂₋ t ₃₋	2 3			4 4	2 3	5, 10, 13 5, 10, 13	

ELECTRICAL CHARACTERISTICS (continued)

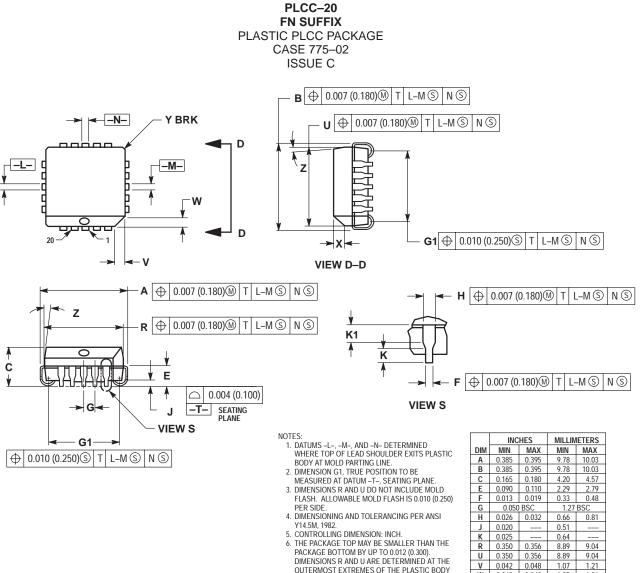
					TEST VO	LTAGE VALU	JES (Volts)		
		@ Test Te	mperature	V _{IHH} *	VILH*	VIHL*	V _{ILL} *	VEE	1
			–30°C	+0.110	-0.890	-1.890	-2.890	-5.2	1
			+25°C	+0.190	-0.850	-1.810	-2.850	-5.2	1
			+85°C	+0.300	-0.825	-1.700	-2.825	-5.2	
			Pin	TEST V	OLTAGE AP	PLIED TO P	INS LISTED	BELOW	
Character	istic	Symbol	Under Test	VIHH*	VILH*	VIHL*	V _{ILL} *	VEE	(VCC) Gnd
Power Supply Drain (Current	١ _E	8					8	1, 16
Input Current		linH	4					8	1, 16
		l _{inL}	4					8, 4	1, 16
Output Voltage	Logic 1	VOH	2 3					8 8	1, 16 1, 16
Output Voltage	Logic 0	VOL	2 3					8 8	1, 16 1, 16
Threshold Voltage	Logic 1	VOHA	2 3					8 8	1, 16 1, 16
Threshold Voltage	Logic 0	VOLA	2 3					8 8	1, 16 1, 16
Reference Voltage		V _{BB}	11					8	1, 16
Common Mode Rejec	ction Test	VOH	2 3	4	5	5	4	8 8	1, 16 1, 16
		V _{OL}	2 3	4	5	5	4	8 8	1, 16 1, 16
Switching Times	(50 Ω Load)							–3.2 V	+2.0 V
Propagation Delay		t ₄₊₂₊ t ₄₋₂₋ t ₄₊₃₋ t ₄₋₃₊	2 2 3 3					8 8 8 8	1, 16 1, 16 1, 16 1, 16 1, 16
Rise Time	(20 to 80%)	t ₂₊ t ₃₊	2 3					8 8	1, 16 1, 16
Fall Time	(20 to 80%)	t ₂₋ t ₃₋	2 3					8 8	1, 16 1, 16

* V_{IHH} = Input Logic 1 level shifted positive one volt for common mode rejection tests V_{ILH} = Input Logic 0 level shifted positive one volt for common mode rejection tests

 V_{IHL} = Input Logic 0 level shifted negative one volt for common mode rejection tests V_{ILL} = Input Logic 0 level shifted negative one volt for common mode rejection tests

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

PACKAGE DIMENSIONS



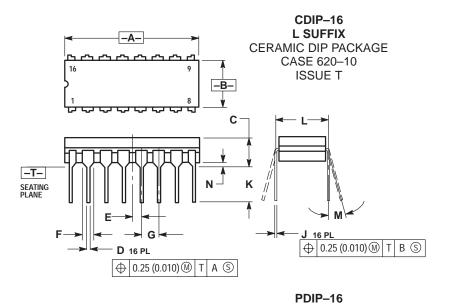
OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP INCLUDING ANY MISMATCH BE IWEEN THE TOP AND BOTTOM OF THE PLASTIC BODY. 7. DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940).

THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025

В	0.385	0.395	9.78	10.03
С	0.165	0.180	4.20	4.57
Ε	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050	BSC	1.27	BSC
Н	0.026	0.032	0.66	0.81
J	0.020		0.51	
K	0.025		0.64	
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
٧	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
Х	0.042	0.056	1.07	1.42
Y		0.020		0.50
Z	2 °	10 °	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040		1.02	

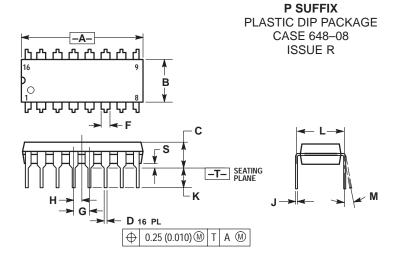
(0.635).

PACKAGE DIMENSIONS



NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL. 4. DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC BODY.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.750	0.785	19.05	19.93	
В	0.240	0.295	6.10	7.49	
С		0.200		5.08	
D	0.015	0.020	0.39	0.50	
Е	0.050	BSC	1.27 BSC		
F	0.055	0.065	1.40	1.65	
G	0.100	BSC	2.54 BSC		
Н	0.008	0.015	0.21	0.38	
К	0.125	0.170	3.18	4.31	
L	0.300	BSC	7.62	BSC	
Μ	0 °	15°	0 °	15 °	
Ν	0.020	0.040	0.51	1.01	



NOTES: 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH. 3. DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL. 4. DIMENSION B DOES NOT INCLUDE MOLD FLASH. 5. ROUNDED CORNERS OPTIONAL.

	INC	HES	MILLIN	IETERS	
DIM	MIN	MAX	MIN	MAX	
Α	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27 BSC		
J	0.008	0.015	0.21	0.38	
К	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
М	0°	10 °	0 °	10 °	
S	0.020	0.040	0.51	1.01	

<u>Notes</u>

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